

Seminarraum F229-3(2. Stock, Physik Flachbau), Seminarbeginn **16:30** Uhr

Datum	SprecherIn/Institut	Thema
18.11.2019		
25.11.2019	Lukas Grünewald	Nanoscale imaging and chemical analysis assisted by machine learning
02.12.2019	Stefan Lux	Characterization of tomography techniques in electron microscopy
09.12.2019	Dr. Tobias Klein Physikalisch-Technische Bundesanstalt Braunschweig	Charaterization of nanoparticles using the transmission mode of scanning electron mircroscopes (TSEM)
16.12.2019		
13.01.2020	Milena Hugenschmidt	Characterization and Mitigation of Electron-Beam-Induced Carbon Contamination and Analysis of Thin-Layer MOFs as Host for Metal Nanoparticles
20.01.2020	Martin Obermair	<i>Cancelled</i>
03.02.2020 15:30	Johannes Schmieg	All Solid State Li-ion Batteries: Preparation and Characterization
10.02.2020 10:30	Martin Obermair	Transmission electron microscopy with phase plates in experiment and simulation
10.02.2020	Meiken Falke BrukerNano GmbH	STEM/EDXS-Analysis using Zeta-Factor method